

Notice of References Cited	Application/Control No. 10/709,027	Applicant(s)/Patent Under Reexamination SUEN ET AL.	
	Examiner James A. Dudek	Art Unit 2871	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,829,071	12-2004	Allen et al.	359/247
	B	US-6,746,130	06-2004	Ohkawa, Shingo	362/617
	C	US-6,595,652	07-2003	Oda et al.	362/609
	D	US-6,568,819	05-2003	Yamazaki et al.	362/619
	E	US-6,515,785	02-2003	Cobb et al.	359/247
	F	US-6,404,468	06-2002	Niwano et al.	349/64
	G	US-6,364,497	04-2002	Park et al.	362/627
	H	US-6,334,690	01-2002	Ohkawa, Shingo	362/613
	I	US-6,309,080	10-2001	Sasako et al.	362/620
	J	US-6,222,689	04-2001	Higuchi et al.	359/837
	K	US-6,222,598	04-2001	Hiyama et al.	349/65
	L	US-6,191,833	02-2001	Hirakata, Junichi	349/61
	M	US-5,914,759	06-1999	Higuchi et al.	349/57

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.